



44 FARRAND STREET
BLOOMFIELD, NJ 07003
(973) 748-5089

NTE2969
MOSFET
N-Channel, Enhancement Mode
High Speed Switch

Features:

- Avalanche Rugged Technology
- Rugged Gate Oxide Technology
- Low Input Capacitance
- Improved Gate Charge
- Extended Safe Operating Area
- Lower Leakage Current
- Low Static Drain-Source On-State Resistance

Absolute Maximum Ratings:

Drain-Source Voltage, V_{DSS}	400V
Drain Current, I_D Continuous		
$T_C = +25^\circ\text{C}$	25A
$T_C = +100^\circ\text{C}$	15.1A
Pulsed (Note 1)	100A
Gate-Source Voltage, V_{GS}	$\pm 30\text{V}$
Gate Current (Pulsed), I_{GM}	$\pm 1.5\text{A}$
Single Pulsed Avalanche Energy (Note 2), E_{AS}	1429mJ
Avalanche Current (Note 1), I_{AS}	25A
Repetitive Avalanche Energy (Note 1), E_{AR}	27.8mJ
Peak Diode Recovery dv/dt (Note 3), dv/dt	4.0V/ns
Total Power Dissipation ($T_C = +25^\circ\text{C}$), P_D	278W
Derate Above 25°C	$2.22\text{W}/^\circ\text{C}$
Operating Junction Temperature Range, T_J	-55° to $+150^\circ\text{C}$
Storage Temperature Range, T_{stg}	-55° to $+150^\circ\text{C}$
Maximum Lead Temperature (During Soldering, 1/8" from case, 5sec), T_L	$+300^\circ\text{C}$
Thermal Resistance:		
Maximum Junction-to-Case, R_{thJC}	$0.45^\circ\text{C}/\text{W}$
Typical Case-to-Sink, R_{thCS}	$0.24^\circ\text{C}/\text{W}$
Maximum Junction-to-Ambient, R_{thJA}	$40^\circ\text{C}/\text{W}$

Note 1. Repetitive Rating: Pulse width limited by maximum junction temperature.

Note 2. $L = 4\text{mH}$, $I_{AS} = 25\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 27\Omega$, Starting $T_J = +25^\circ\text{C}$.

Note 3. $I_{SD} \leq 25\text{A}$, $di/dt \leq 320\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = +25^\circ\text{C}$.

Electrical Characteristics: ($T_C = +25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain–Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	400	—	—	V
Breakdown Voltage Temperature Coefficient	$\Delta \text{BV}/\Delta T_J$	$I_D = 250\mu\text{A}$	—	0.20	—	$\text{V}/^\circ\text{C}$
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = 5\text{V}, I_D = 250\mu\text{A}$	2.0	—	4.0	V
Gate–Source Leakage Forward	I_{GSS}	$V_{\text{GS}} = 30\text{V}$	—	—	100	nA
Gate–Source Leakage Reverse	I_{GSS}	$V_{\text{GS}} = -30\text{V}$	—	—	-100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 400\text{V}, V_{\text{GS}} = 0$	—	—	10	μA
		$V_{\text{DS}} = 320\text{V}, T_C = +150^\circ\text{C}$	—	—	100	μA
Static Drain–Source ON Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 12.5\text{A}$, Note 4	—	—	0.2	Ω
Forward Transconductance	g_{fs}	$V_{\text{DS}} = 50\text{V}, I_D = 12.5\text{A}$, Note 4	—	18.91	—	mhos
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 25\text{V}, f = 1\text{MHz}$	—	3180	4130	pF
Output Capacitance	C_{oss}		—	435	500	pF
Reverse Transfer Capacitance	C_{rss}		—	200	240	pF
Turn–On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 200\text{V}, I_D = 25\text{A}, R_G = 5.3\Omega$, Note 4, Note 5	—	22	55	ns
Rise Time	t_r		—	22	60	ns
Turn–Off Delay Time	$t_{\text{d}(\text{off})}$		—	127	260	ns
Fall Time	t_f		—	38	85	ns
Total Gate Charge	Q_g	$V_{\text{GS}} = 10\text{V}, I_D = 25\text{A}, V_{\text{DS}} = 320\text{V}$, Note 4, Note 5	—	140	182	nC
Gate–Source Charge	Q_{gs}		—	21	—	nC
Gate–Drain (“Miller”) Charge	Q_{gd}		—	64.8	—	nC
Source–Drain Diode Ratings and Characteristics						
Continuous Source Current	I_S	(Body Diode)	—	—	25	A
Pulse Source Current	I_{SM}	(Body Diode) Note 1	—	—	100	A
Diode Forward Voltage	V_{SD}	$T_J = +25^\circ\text{C}, I_S = 25\text{A}, V_{\text{GS}} = 0\text{V}$, Note 4	—	—	1.5	V
Reverse Recovery Time	t_{rr}	$T_J = +25^\circ\text{C}, I_F = 25\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$	—	484	—	ns
Reverse Recovery Charge	Q_{rr}		—	7.6	—	μC

Note 1. Repetitive Rating: Pulse width limited by maximum junction temperature.

Note 4. Pulse Test: Pulse Width $\leq 250\mu\text{s}$, Duty Cycle $\leq 2\%$.

Note 5. Essentially independent of operating temperature.

